# MOSFET – Power, Single, N-Channel 80 V, 2.8 mΩ, 157 A

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- These Devices are Pb-Free and are RoHS Compliant

## MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V <sub>DSS</sub>	80	V
Gate-to-Source Voltage			V <sub>GS</sub>	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	157	Α
Current R <sub>θJC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		111	
Power Dissipation	State	T <sub>C</sub> = 25°C	P <sub>D</sub>	166	W
R <sub>0JC</sub> (Note 1)		T <sub>C</sub> = 100°C	1	83	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	23	Α
Current R <sub>θJA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		16	
Power Dissipation	State	T <sub>A</sub> = 25°C	P <sub>D</sub>	3.8	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C	1	1.9	
Pulsed Drain Current	$T_A = 25$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	900	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +175	°C
Source Current (Body Diode)			Is	138	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 12.2 A)			E <sub>AS</sub>	960	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

## THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	0.9	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39	

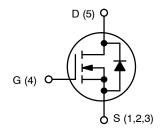
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



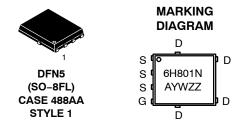
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V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
80 V	2.8 mΩ @ 10 V	157 A



**N-CHANNEL MOSFET** 



A = Assembly Location

Y = Year
W = Work Week
ZZ = Lot Traceability

## **ORDERING INFORMATION**

See detailed ordering, marking and shipping information on page 5 of this data sheet.

## **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

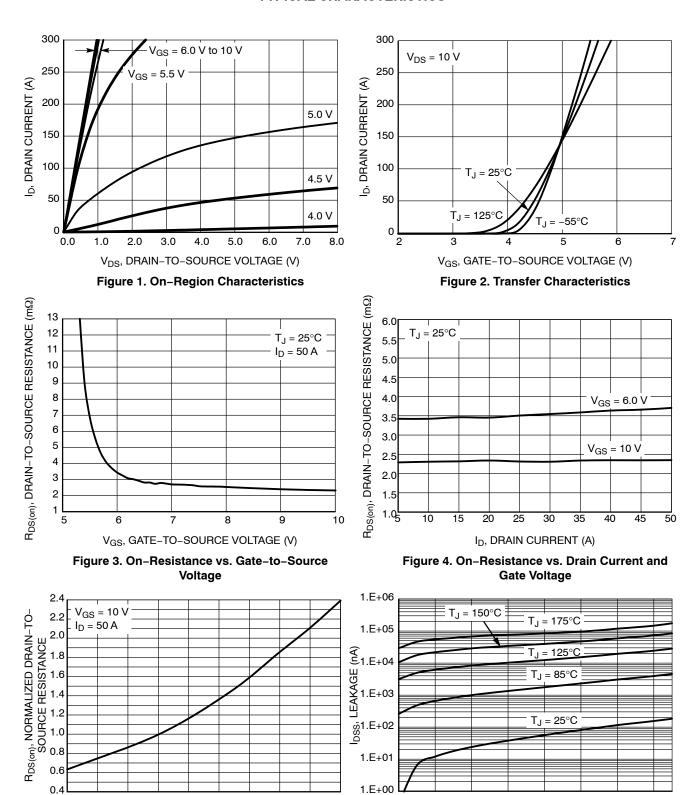
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		80			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				38		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$	T <sub>J</sub> = 25 °C			10	
		V <sub>DS</sub> = 80 V	T <sub>J</sub> = 125°C			100	μΑ
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 V, V_{G}$	<sub>S</sub> = 20 V			100	nA
ON CHARACTERISTICS (Note 4)							
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D = 250 \mu A$		2.0		4.0	V
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				7.2		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 50 A		2.3	2.8	
		V <sub>GS</sub> = 6 V	I <sub>D</sub> = 50 A		3.3	4.4	mΩ
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> =15 V, I <sub>D</sub> = 50 A			128		S
CHARGES, CAPACITANCES & GATE RE	SISTANCE						-
Input Capacitance	C <sub>ISS</sub>				4120		pF
Output Capacitance	Coss			586			
Reverse Transfer Capacitance	C <sub>RSS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 40 V			22		
Output Charge	Q <sub>OSS</sub>				87		nC
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 40 V; I <sub>D</sub> = 50 A			64		nC
Threshold Gate Charge	Q <sub>G(TH)</sub>				11		
Gate-to-Source Charge	Q <sub>GS</sub>				19		
Gate-to-Drain Charge	$Q_{GD}$				13		
Plateau Voltage	$V_{GP}$				5.0		V
SWITCHING CHARACTERISTICS (Note	5)						
Turn-On Delay Time	t <sub>d(ON)</sub>	$V_{GS}$ = 10 V, $V_{DS}$ = 64 V, $I_{D}$ = 50 A, $R_{G}$ = 2.5 $\Omega$			25		- ns
Rise Time	t <sub>r</sub>				74		
Turn-Off Delay Time	t <sub>d(OFF)</sub>				70		
Fall Time	t <sub>f</sub>				19		
DRAIN-SOURCE DIODE CHARACTERIS	STICS						
Forward Diode Voltage	V <sub>SD</sub>	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 50 A	T <sub>J</sub> = 25°C		0.8	1.2	
			T <sub>J</sub> = 125°C		0.7		V
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dI_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $I_{S} = 50 \text{ A}$			64		ns
Charge Time	t <sub>a</sub>				36		
Discharge Time	t <sub>b</sub>				28		
Reverse Recovery Charge	Q <sub>RR</sub>				98		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.

5. Switching characteristics are independent of operating junction temperatures.

## **TYPICAL CHARACTERISTICS**



T<sub>J</sub>, JUNCTION TEMPERATURE (°C)

Figure 5. On-Resistance Variation with

Temperature

50

75

-50

-25

Figure 6. Drain-to-Source Leakage Current vs. Voltage

V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V)

45

55

75

35

150

175

15

25

## **TYPICAL CHARACTERISTICS**

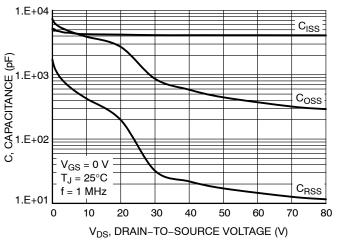


Figure 7. Capacitance Variation

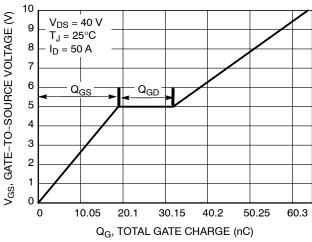


Figure 8. Gate-to-Source vs. Total Charge

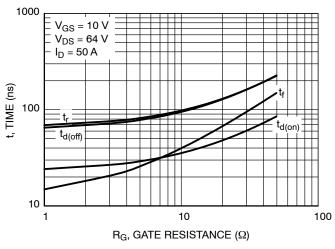


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

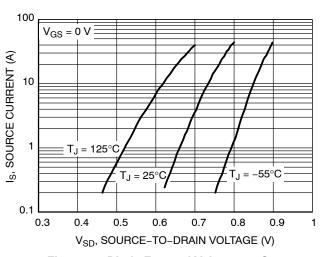


Figure 10. Diode Forward Voltage vs. Current

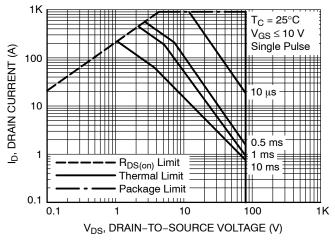


Figure 11. Maximum Rated Forward Biased Safe Operating Area

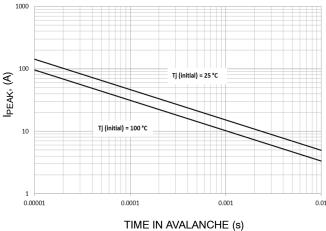


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

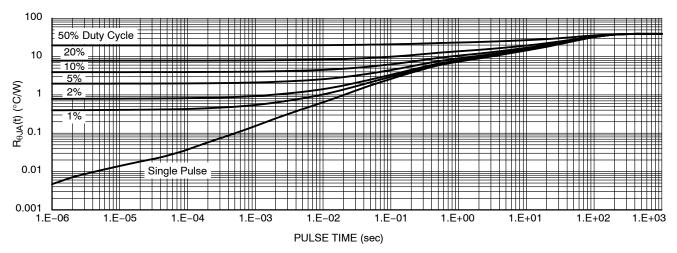


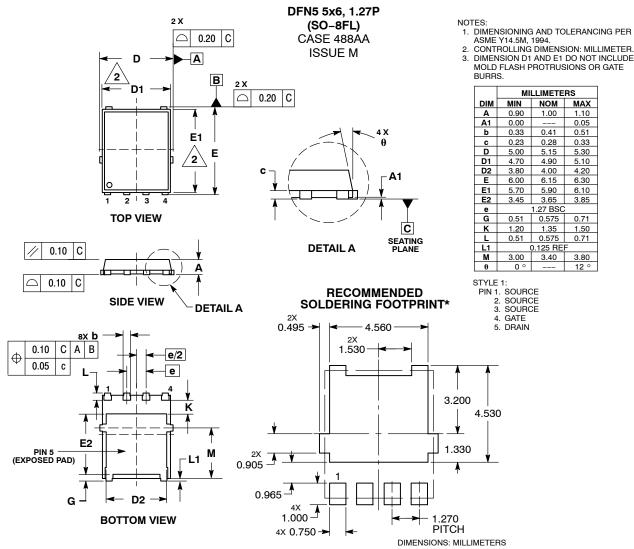
Figure 13. Thermal Characteristics

### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NTMFS6H801NT1G	6H801N	DFN5 (Pb-Free)	1500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

#### PACKAGE DIMENSIONS



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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